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PATENT NUMBER and
ISSUE DATE

U.S. UTILITY Patent Application

APPL NUM 10029788	FILING DATE 10/26/2001	CLASS 451	SUBCLASS 044	GAU 3723	EXAMINER Eley
** APPLICANTS: Curran David; Guldri Richard; Pressnall William;					
** CONTINUING DATA VERIFIED: THIS APPLN CLAIMS BENEFIT OF 60/248,170 11/13/2000					
BEST AVAILABLE COPY					
** FOREIGN APPLICATIONS VERIFIED:					
PG-PUB <input type="checkbox"/>		DO NOT PUBLISH <input type="checkbox"/>		RESCIND <input type="checkbox"/>	
Foreign priority claimed <input type="checkbox"/> yes <input type="checkbox"/> no				ATTORNEY DOCKET NO	
35 USC 119 conditions met <input type="checkbox"/> yes <input type="checkbox"/> no				TI-29038	
Verified and Acknowledged Examiners's initials <i>de</i>					
TITLE : Method and system for reducing thickness of spin-on glass on semiconductor wafers					
<small>U.S. DEPT. OF COMM./PAT. & TM.-PTO-436L (Rev. 12-94)</small>					

NOTICE OF ALLOWANCE MAILED		CLAIMS ALLOWED	
		Total Claims	
		Print Claim for O.G.	
ISSUE FEE		DRAWING	
Amount Due	Date Paid	Sheets Drwg.	Figs. Drwg.
		Print Fig.	
<input type="checkbox"/> TERMINAL DISCLAIMER		Primary Examiner	
		Application Examiner	
		PREPARED FOR ISSUE	
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